

Message from the Editor-In-Chief

On December 31 2015, I completed the first year of my term as Editor-In-Chief (EIC); as you will read further in this editorial, I am pleased to report that the IEEE Transactions on Nanotechnology (TNANO) continues to strengthen its reputation and consolidate its role as the flagship Transactions of the IEEE Nanotechnology Council (NTC). 2015 has been an outstanding year for TNANO; Manuscript Central Scholar 1 reports the following very impressive statistics for the 2015 calendar year:

Number of submitted original papers: 647

Number of revised-and-resubmitted papers: 99

Total number of papers received: 746

Acceptance rate: 30.4%

Rejection rate: 51.6%

Revise-and-resubmit rate: 18%

All the above numbers are the absolute best in quantitative and qualitative terms (such as for the highest selectivity) in the 14 years of existence of TNANO and reflect the steady and continued growth in terms of quality and quantity of this periodical.

My sincere thanks goes to all constituencies of TNANO for such an accomplishment: the readers, supporters, contributors, reviewers and the Editorial Board; an additional and special acknowledgment for her day-by-day support in all operations is owned to the TNANO Periodical Assistant, Ms. Allyson King of Allen Press.

We are leveraging the past and the outstanding results of 2015 well into 2016. TNANO is closely aligned with the other technical activities of the IEEE NTC,

We are in the last stages of the review process for the Special Issues and Sections consisting of selected and expanded manuscripts presented at the following NTC sponsored events: IEEE NANO, NANOFIM and NMDC 2015. The responses from the invited authors has been excellent; 88 manuscripts have been received for these Special Sections and Issues. I am very grateful to the Guest Editors for all the work (both done and on-going) to ensure the timely publication of these articles with professionalism and fairness in the peer-review process.

As found on the web site of TNANO (<http://sites.ieee.org/tnano/>) many new Special Sections/Issues will be executed in 2016, some of them are being planned in coordination with NTC sponsored events, others on specific topics of interests; they are all in an open paper call format, so there is ample of opportunities for publishing your best work in a focused venue; when submitting a paper to a Special Issue/Section please specify its name in the cover letter, so that a prompt assignment to the correct Guest Editors can be made. If you wish to organize a Special Issue/Section on a topic of relevance to TNANO, please do not hesitate to contact me.

At this time of growth, I am also very aware that manuscripts accepted through the traditional submission process should not be incurring in a long publication delay due to Special Issues or Sections; so, a nearly 10% increase in page allocation over 2015 has been granted for next year to accommodate a likely increase in number of published articles and alleviate any publication delay. We are striving not only to reduce the electronic publication and availability of your accepted manuscript as an “Early Release” in IEEE Xplore, but also to reduce the time to print in hard copy.

The Editorial Board of TNANO continues to grow to sustain the increase in the number of submissions; TNANO has now 9 Editors and 32 Associate Editors. Bibliographical notes of all members of the Editorial Board can be found at the

TNANO web site; this substantial expansion has played a primary role in the significant reduction of the delay in the review process, thus allowing TNANO to continue to attract the best contributions in nanotechnology engineering for timely publication. I would like to take this opportunity to thank the following colleagues who have retired from the Board: Drs. X. Li, K. Suganuma and L. E. Wernersson. I wish them the very best in their professional careers as they have contributed significantly to the success of TNANO.

As a further news, the NTC Executive Committee has approved the procedure for awarding the “Best Paper Award” of TNANO (as initiated by Dr. Sorin Cotofana, AEIC). This yearly award will be made starting in 2017 for the best paper published in TNANO in 2016; all details of this award can found at

<http://sites.ieee.org/tnano/2015/12/2016-tnano-best-paper-award/>

The TNANO website continues to enlarge its contents for a full technical coverage to the community. On a monthly basis, a published paper is selected as “The Article-on-Focus”; such a paper is highlighted on the TNANO web site and it may also be a potential candidate for the “Best Paper Award”. Additionally, all links and pointers to the periodical and IEEE services (such as “Browse Latest Issue” or “Submit Manuscript”) as well as “News” are always up-to-date; I invite you to visit this site and pass to me comments and suggestions for improvement.

Also as TNANO does not require to specify the type for a submission with respect to manuscript length, I would like to encourage potential authors of a technical letter (i.e. a manuscript up to 4 pages long) to consider IEEE Nanotechnology Express (ENANO) as a venue for publication. More details about this NTC sponsored publication can be found at <http://sites.ieee.org/enano/>

Finally, I would like to clarify few items of a clerical but important nature that authors should be aware. As per my previous message, IEEE regulates that all authors must be registered in the official record of Manuscript Central Scholar 1; moreover, a

manuscript for undergoing review must abide by the format and requirements (such as per the 2-column template) mandated by TNANO.

I remind our prospective authors that a previously rejected paper to TNANO cannot be resubmitted; only papers declined under the “revise and resubmit” category can be resubmitted to TNANO for further consideration under an additional round of review (multiple rounds under “revise-and-resubmit” decisions are discouraged).

Submitted articles must not have been previously published or currently submitted for journal publication elsewhere. An extended version of the article appearing in any conference proceedings can be submitted, provided that it has substantially new content with respect to the original conference version. The conference paper must be cited in the main text and the cover letter (or additional documentation) must clearly describe the differences with the conference version and clearly identify the new contributions. As an author, you are responsible for understanding and adhering to the submission guidelines of TNANO.

Be advised that all manuscripts submitted to TNANO are filtered by CrossCheck, a powerful plagiarism detection software system. By submitting your work you agree to allow IEEE to screen your work. IEEE takes the protection of intellectual property seriously. When plagiarism is detected and found, penalties can be severe and may include strict banning from publishing in all IEEE titles.

As you can see in my message, the prospects for 2016 look excellent; there are many signs that the momentum from 2015 can be continued at a faster pace as both TNANO and the NTC enlarge their technical events and publication activities. Needless to say I am committed to a growth that as primary and only measure places unabated quality in all of the endeavors. While I am committed to ensure that TNANO will meet the highest standards of selectivity in the review process, I regard the impact of the published articles as the ultimate measure of excellence. So I look forward to receive more manuscripts of the highest quality from authors in 2016.

Let me conclude on a personal note: do not hesitate to contact me at lombardi@ece.neu.edu or chat if we meet at a professional meeting; I will be delighted to answer questions and provide further clarification and information on any aspect related to TNANO.

I really appreciate your support and look forward to work closely with everyone in 2016 and do even better than 2015.

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